

# High-d (Heidi) Swiss Army Knife

Luis Oala

August 9, 2020



# Outline

Justin Gilmer: High-d Error Rates

Eric Nalisnick: Degenerate OOD detection in High-d

vd Oord and Theis: How Likelihoods Can Break in High-d

Charu Aggarwal: High-d Metric Surprises



## Justin Gilmer: High-d Error Rates



# Justin Gilmer: High-d Error Rates

## Setup<sup>1</sup>

- ▶ **error set**  $E$ : set of points in the input space on which the classifier makes an incorrect prediction
- ▶ **corruption robustness**  $\mathbb{P}_{x \sim q}[x \notin E]$ : probability that a random sample from the  $q$  is not an error, under a given corrupted image distribution  $q$ .
- ▶ **adversarial robustness**  $\mathbb{P}_{x \sim p}[d(x, E) > \epsilon]$ : probability that a random sample from  $p$  is not within distance  $\epsilon$  of some point in the error set, where metric on the input space  $d(x, E)$  denotes the distance from clean input  $x$  to the nearest point in  $E$  (also based on work by [2])
- ▶ **error rate**  $\mu$ :  $\mathbb{E}_{x \sim \mathcal{N}(x_0; \sigma^2 I)}[x \in E]$ , with some clean image  $x_0$  and the Gaussian distribution  $\mathcal{N}(x_0; \sigma^2 I)$
- ▶  $\sigma(x_0, \mu)$ : For a fixed  $\mu$ , the  $\sigma$  for which the error rate is  $\mu$

---

<sup>1</sup><https://slideslive.com/38930579/>



## Justin Gilmer: High-d Error Rates (cont'd)

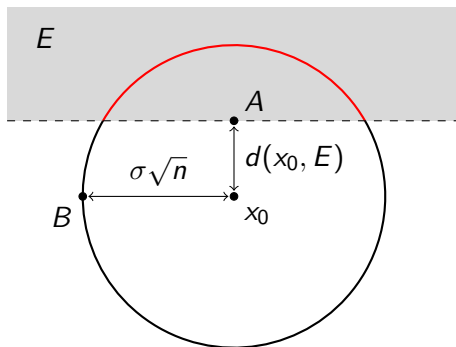


Figure 1: Sphere cutting illustration by [3]



# Justin Gilmer: High-d Error Rates (cont'd)

## Analysis

Letting  $d$  denote  $l_2$  distance, we have

$$d(x_0, E) = -\sigma(x_0, \mu)\Phi^{-1}(\mu), \quad (1)$$

where

$$\Phi(t) = \frac{1}{\sqrt{2\pi}} \int_{-\infty}^t \exp(-x^2/2) dx$$

is the cdf of the univariate standard normal distribution. (Note that  $\Phi^{-1}(\mu)$  is negative when  $\mu < \frac{1}{2}$ .)



# Justin Gilmer: High-d Error Rates (cont'd)

## Observations

- Equation 1 does not depend on  $n$

$n$	$\sigma\sqrt{n}$	$d(x_0, E)$
3	0.17	0.23
150,528 (ImageNet)	38.8	0.23

**Table 1:** Linear model - distance of typical corrupted input ( $\sigma\sqrt{n}$ ) and distance of nearest error ( $d(x_0, E)$ ) under varying input dimension  $n$

- $\frac{d(x_0, E)}{\sigma\sqrt{n}}$



# Justin Gilmer: High-d Error Rates (cont'd)

## Geometric Interpretation of Equation 1: Gaussian Annulus Theorem

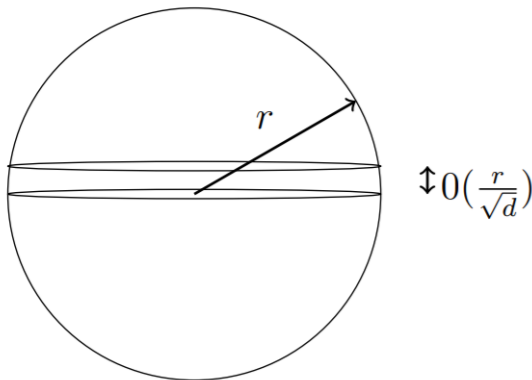


Figure 2: Equator concentration of spherical volume and surface area <sup>2</sup>

<sup>2</sup><https://www.cs.cmu.edu/~venkatg/teaching/CStheory-infoage/>





# Eric Nalisnick: Degenerate OOD detection in High-d



# Eric Nalisnick: Degenerate OOD detection in High-d

Decision rule:

$$p(\mathbf{X}^* | \text{IN}) > \frac{p(\mathbf{X}^* | \text{OUT}) p(\text{OUT})}{p(\text{IN})}$$

(a)

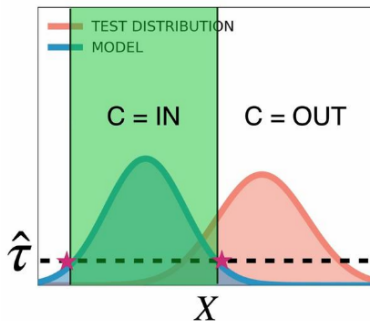
Decision rule:

$$\text{DGM } q(\mathbf{X}^*) > \underbrace{\frac{\text{UNIFORM}(\mathbf{X}^*) p(\text{OUT})}{p(\text{IN})}}_{\hat{\tau}}$$

Implies classifier is just a threshold on the density function:

$$q(\mathbf{X}^*) > \hat{\tau}$$

(b)



(c)



# Eric Nalisnick: Degenerate OOD detection in High-d (cont'd)

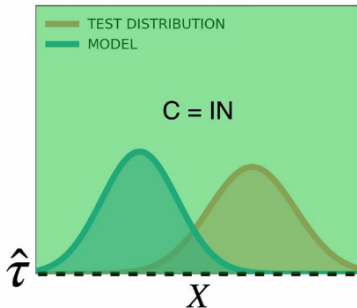
**PROBLEM:** In high-dimensions, the uniform OOD model becomes degenerate.

$$\text{UNIFORM}(\mathbf{x}) = \frac{1}{(b-a)^D} \rightarrow 0 \quad \text{as } D \rightarrow \infty$$

Which leads to the degenerate threshold:

$$q(\mathbf{X}^*) > \text{UNIFORM}(\mathbf{X}^*) \frac{p(\text{OUT})}{p(\text{IN})} = 0$$

(d)



(e)

Note: All visualizations by Eric Nalisnick, check his talk at <https://icml.cc/virtual/2020/workshop/5742>

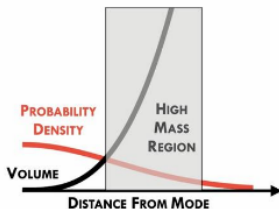


# Eric Nalisnick: Degenerate OOD detection in High-d (cont'd)

## Bonus Heidi

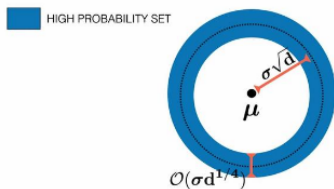
$$m = V \times \rho$$

In high dimensions, probability mass concentrates *away* from the mode.



(f)

In high dimensions, probability mass concentrates *away* from the mode.



HIGH DIMENSIONAL GAUSSIAN

(g)



## vd Oord and Theis: How Likelihoods Can Break in High-d



# vd Oord and Theis: How Likelihoods Can Break in High-d

[4, 5]

## Great log-likelihood and poor samples

- ▶  $p$ : density of a model for  $d$  dimensional data  $\mathbf{x}$  which performs arbitrarily well with respect to average log-likelihood
- ▶  $q$ : corresponds to some bad model (e.g., white noise)
- ▶ Then samples generated by the mixture model  $0.01p(\mathbf{x}) + 0.99q(\mathbf{x})$  will come from the poor model 99% of the time
- ▶ Yet the log-likelihood per pixel will hardly change if  $d$  is large:  
$$\log [0.01p(\mathbf{x}) + 0.99q(\mathbf{x})] \geq \log [0.01p(\mathbf{x})] = \log p(\mathbf{x}) - \log 100$$
  
For high-dimensional data,  $\log p(\mathbf{x})$  will be proportional to  $d$  while  $\log 100$  stays constant.



## Charu Aggarwal: High-d Metric Surprises







[1] <https://bib.dbvis.de/uploadedFiles/155.pdf>





# References I

-  Charu C Aggarwal, Alexander Hinneburg, and Daniel A Keim. “On the surprising behavior of distance metrics in high dimensional space”. In: *International conference on database theory*. Springer. 2001, pp. 420–434.
-  Alhussein Fawzi, Seyed-Mohsen Moosavi-Dezfooli, and Pascal Frossard. “Robustness of classifiers: from adversarial to random noise”. In: *Advances in Neural Information Processing Systems*. 2016, pp. 1632–1640.
-  Justin Gilmer et al. “Adversarial examples are a natural consequence of test error in noise”. In: *International Conference on Machine Learning*. 2019, pp. 2280–2289.
-  Aäron van den Oord and Joni Dambre. “Locally-connected transformations for deep gmms”. In: *International Conference on Machine Learning (ICML): Deep learning Workshop*. 2015, pp. 1–8.



# References II



Lucas Theis, Aäron van den Oord, and Matthias Bethge. “A note on the evaluation of generative models”. In: *arXiv preprint arXiv:1511.01844* (2015).

